[]

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE UTILITY PATENT APPLICATION TRANSMITTAL LETTER



Attorney Docket No.: SC11210

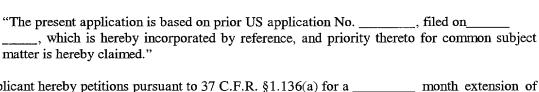
Mailing Date: October 6, 2000

Express Mailing Label No .: EJ140606710US

To: Assistant Commissioner for Patents

Box Patent Application Washington D.C., 20231

Dear Sir: Transmitted herewith for filing under 37 C.F.R. 1.53(b) is a: \boxtimes New Nonprovisional Utility Patent Application; or Continuation-In-Part (Continuation No. ______, filed on ______, having U.S. Examiner _____, in Group Art Unit _____ Continuation-In-Part (CIP); Of: Jonathan F. Gorrell and Gordana S. Nielsen For: MICROMACHINED COMPONENT AND METHOD OF MANUFACTURE \boxtimes 3 sheets of INFORMAL drawings and 17 pages of specification and claims. M UNSIGNED oath or declaration combined with Power of Attorney on 2 pages. Copy of oath or declaration from prior U.S. application serial no. The following named inventor(s) from the prior application are hereby deleted from this application in accordance with 1.63(d)(2)37 C.F.R. and 1.33(b): Foreign priority to EPO patent application having serial number _____ and a filing date of _____, is hereby claimed under 35 USC 119. An Assignment Transmittal Letter and Assignment of the invention to Motorola, Inc. M An Information Disclosure Statement (IDS), with PTO-1449, and 1 citation copies. \boxtimes Return Receipt Postcard. Preliminary Amendment. Please cancel pending claims _____. Incorporation by Reference (for Continuation/Division/CIP application). The entire disclosure of the prior application, from which a copy of the oath or declaration is supplied, is considered as being part of the disclosure of the accompanying application and is hereby incorporated by reference therein. Since the present application is based on a prior US application, please amend the specification by adding the following sentence before the first sentence of the specification:



Applicant hereby petitions pursuant to 37 C.F.R. §1.136(a) for a month extension or
time for response to the outstanding Official Action mailed The period for response
was previously set to elapse, and is accordingly hereby extended to,
which is still within the six-month statutory period for response (35 U.S.C. § 133) which elapses
The reason for this petition is that a Division, Continuation, or CIP is being filed
and it is desired to maintain the present application in pending condition pursuant to 35 USC §
120 through at least the filing of the Division, Continuation, or CIP application. The required
Extension Fee established by 37 C.F.R. § 1.17(a) pursuant to 35 U.S.C. § 41(a) (8) is:

EXTENSION	FEE
First Month	\$110.00
Second Month	\$390.00
☐ Third Month	\$890.00
Fourth Month	\$1,390.00
☐ Fifth Month	\$1,890.00

 \boxtimes The filing fee is calculated as follows:

CLAIMS AS FILED, LESS ANY CANCELED BY AMENDMENT

FOR	NUMBER OF CLAIMS	NUMBER EXTRA	RATE		FEE
TOTAL CLAIMS	25 - 20 =	5	x \$18	=	\$90.00
INDEPENDENT CLAIMS	2 - 3 =	0	x \$80	=	\$ 0.00
MULTIPLE DEPENDENT CLAIMS \$270				=	\$ 0.00
BASIC FEE				=	\$ 710.00
TOTAL FILING FEE				=	\$ 800.00

- M Please charge Deposit Account No. 13-4771 in the amount of \$__800.00 for the Total Filing Fee, and the Extension Fee under 37 C.F.R. §1.136(a), if applicable.
- 図 The Commissioner is hereby authorized to charge any additional fees which may be required now or in the future during the entire pendency of this application under 37 C.F.R. 1.16 or 37 C.F.R. 1.17, including any present or future time extension fees which may be required, or credit any overpayment to Deposit Account No. 13-4771.
- \boxtimes This sheet is submitted in duplicate.

This transmittal letter has 2 total pages.

Charles W. Bethards

REG. NO.

DATE

Attorney of Record

Telephone No.: (480) 441-4237 Facsimile No.: (480) 441-5220

les w. Lethande

Motorola, Inc.

Customer Number: 23330

15

20

25

MICROMACHINED COMPONENT AND METHOD OF MANUFACTURE

Field of the Invention

This invention relates to electronics, in general, and to micromachined components and methods of manufacture, in particular.

Background of the Invention

The manufacturing of a micromachined component includes the removal of a sacrificial layer underneath an electrically conductive and/or structural layer. The removal of the sacrificial layer typically involves the use of a wet or liquid acid etchant in an acid hood. The micromachined component needs to be dried after the removal of the sacrificial layer because of the use of the liquid acid etchant to remove the sacrificial layer.

One technique for drying a micromachined component involves the use of a supercritical carbon dioxide drying process. This particular drying process reduces or eliminates release stiction in the micromachined component. After removing the sacrificial layer and before performing the supercritical carbon dioxide drying process, the micromachined component is immersed in methanol, which is an organic solvent.

The use of methanol, however, creates a problem in manufacturing the micromachined component because organic solvents are not permitted in an acid hood. Therefore, after the sacrificial layer is removed by the liquid acid etchant in the acid hood, the micromachined component is transported to a solvent hood in which the component is rinsed with methanol. The transportation of the

15

20

component between hoods decreases the manufacturing throughput and also increases the cost of the manufacturing process.

Accordingly, a need exists for a method of manufacturing an electronic component and the resultant component thereof where the manufacturing process for the micromachined component maintains a high throughput and low cost while eliminating or at least reducing release stiction.

Brief Description of the Drawings

The invention will be better understood from a reading of the following

detailed description, taken in conjunction with the accompanying drawing figures in which:

FIGs. 1 through 3 illustrate cross-sectional views of a portion of a micromachined component after different steps of a manufacturing process in accordance with an embodiment of the invention; and

FIG. 4 illustrates a flow chart of a method of manufacturing a micromachined component in accordance with an embodiment of the invention.

For simplicity and clarity of illustration, the drawing figures illustrate the general manner of construction, and descriptions and details of well-known features and techniques are omitted to avoid unnecessarily obscuring the invention. Additionally, elements in the drawing figures are not necessarily drawn to scale, and the same reference numerals in different figures denote the same elements.

Furthermore, the terms first, second, third, fourth, fifth and the like in the description and in the claims, if any, are used for distinguishing between similar elements and not necessarily for describing a sequential or chronological order. It

is further understood that the terms so used are interchangeable under appropriate circumstances and that the embodiments of the invention described herein are capable of operation in sequences other than described or illustrated herein.

Moreover, the terms top, bottom, over, under, and the like in the description and in the claims, if any, are used for descriptive purposes and not necessarily for describing relative positions. It is understood that the terms so used are interchangeable under appropriate circumstances and that the embodiments of the invention described herein are capable of operation in orientations other than described or illustrated herein.

10

15

20

5

Detailed Description of the Drawings

FIGs. 1 through 3 illustrate cross-sectional views of a portion of a micromachined component 100 after different steps of a manufacturing process. As an example, micromachined component 100 can be a sensor such as an accelerometer. In a different embodiment, component 100 can be used for biochip or communications applications.

The manufacturing process for component 100 preferably includes using a first non-solvent liquid to etch a sacrificial layer located underneath an electrically conductive and/or structural layer, exposing the electrically conductive and/or structural layer to a second non-solvent liquid that is miscible in carbon dioxide, and supercritical drying component 100 with carbon dioxide. The elimination of the use of an organic solvent such as methanol simplifies the manufacturing process for component 100 because component 100 does not need to be transferred from an acid hood, in which the sacrificial layer is removed, to a solvent hood.

10

15

20

Instead, component 100 can remain in the acid hood after the sacrificial layer is removed, while the electrically conductive and/or structural layer is exposed to the second liquid, until just before component 100 is supercritical dried.

Turning to FIG. 1, component 100 is illustrated to include a substrate 110. Substrate 110 can include a semiconductor, metal, and dielectric layers. In the preferred embodiment, substrate 110 is a semiconductor substrate.

Component 100 also includes an electrically insulative layer 120 overlying substrate 110. When substrate 110 is comprised of a semiconductor layer, layer 120 electrically isolates substrate 110 from the portions of component 100 located over layer 120. Furthermore, when substrate 110 is comprised of a semiconductor layer and when other portions of component 100 located over layer 120 are also comprised of semiconductor layers, layer 120 serves as an etch stop layer to protect substrate 110. As an example, layer 120 can be comprised of silicon nitride, aluminum nitride, or silicon dioxide. In the preferred embodiment, layer 120 is comprised of silicon nitride.

An electrically conductive and/or structural layer 130 is formed over layer 120 and substrate 110. Layer 130 is patterned to provide a bottom capacitor electrode for micromachined component 100. As an example, layer 130 can be comprised of a doped semiconductor material, a metal, or another electrically conductive material. In the preferred embodiment, layer 130 is comprised of heavily doped silicon.

Next, a sacrificial layer 140 is formed over layer 130, layer 120, and substrate 110. Layer 140 is subsequently removed to release a top capacitor electrode of component 100. As an example, layer 140 can be comprised of silicon

10

15

20

dioxide, Phospho-Silicate-Glass (PSG), or germanium. In the preferred embodiment, layer 140 is comprised of PSG.

Subsequently, an electrically conductive and/or structural layer 150 is formed over layer 140, layer 130, layer 120, and substrate 110. A portion of layer 150 forms the top capacitor electrode for component 100. As an example, layer 150 can be comprised of a doped semiconductor material, a metal, or another electrically conductive material. In the preferred embodiment, layer 150 comprises the same material as layer 130.

Next, an optional electrically insulative layer 160 can be formed over layers 150, 140, 130, and 120, and substrate 110. Layer 160 can be used to protect layer 150 when patterning an electrically conductive and/or structural layer (not shown in FIG. 1) overlying layer 150. As an example, layer 160 can be comprised of silicon dioxide, PSG, or silicon nitride.

Turning to FIG. 2, layers 160 and 150 are patterned. During this patterning process, holes 270 are etched into layers 160 and 150. Holes 270 expose portions of layer 140.

Subsequently, as illustrated in FIG. 3, layer 140 (FIG. 2) is etched and removed using a sacrificial etch process. This sacrificial etch process may also remove layer 160 (FIG. 2) as illustrated in FIG. 3. The removal of layer 140 (FIG. 2) releases the top electrode portion of layer 150 such that the released portion of layer 150 is movable relative to layers 130 and 120 and substrate 110.

A first liquid is used to etch layer 140 (FIG. 2). In an embodiment where layer 140 is comprised of silicon dioxide or PSG, the first liquid can be comprised of hydrofluoric acid, which is not a solvent. In this embodiment, the sacrificial

10

15

20

etching process can be performed in an acid hood. In an embodiment where layer 140 is comprised of germanium, the first liquid can be comprised of hydrogen peroxide. In this embodiment, the sacrificial etching process can also be performed in an acid hood. The use of hydrofluoric acid or hydrogen peroxide enables the removal of layer 140 without substantially etching either of layers 130 or 150 when layers 130 and 150 consist essentially of doped silicon.

After etching or removing layer 140 (FIG. 2), layer 150 in FIG. 3 is exposed to a second liquid. This second liquid displaces the first liquid from between layers 150 and 130. In the preferred embodiment, especially where the first liquid is comprised of hydrofluoric acid, the second liquid completely displaces or completely removes the first liquid from component 100. The removal of the first liquid from component 100 terminates the etching process. Layer 150 can be exposed to the second liquid while component 100 remains in the acid hood. The first liquid is preferably miscible in the second liquid. As an example, the second liquid can be comprised of deionized water.

After the first liquid is displaced with the second liquid, layer 150 is exposed to a third liquid. The third liquid displaces the second liquid from between layers 150 and 130. The step of exposing layer 150 to the third liquid can be performed in the acid hood. In the preferred embodiment, the second liquid is miscible in the third liquid. As an example, the third liquid can be comprised of hydrogen peroxide. The step of exposing layer 150 to the third liquid can be eliminated when the first liquid is comprised of hydrogen peroxide.

After the second liquid is displaced by the third liquid, layer 150 is exposed to a fourth liquid. This fourth liquid displaces the third liquid from between layers

10

15

20

150 and 130. This step of exposing layer 150 to the fourth liquid can be performed in the acid hood. In the preferred embodiment, the third liquid is miscible in the fourth liquid. As an example, the fourth liquid can be comprised of deionized water. Also in the preferred embodiment, the second and fourth liquids are the same so that a single liquid is provided for the second and fourth liquids. The step of exposing layer 150 to the fourth liquid can be eliminated when the first liquid is comprised of hydrogen peroxide.

After the third liquid is displaced by the fourth liquid, layer 150 is exposed to a fifth liquid. The fifth liquid displaces the fourth liquid from between layers 150 and 130. The step of exposing layer 150 to the fifth liquid can be performed in the acid hood. In the preferred embodiment, the fifth liquid is inorganic, preferably does not etch or corrode any component of 100, and is also miscible in carbon dioxide. As an example, the fifth liquid can be comprised of carboxylic acid. An example of a suitable type of carboxylic acid is acetic acid, particularly glacial or non-diluted acetic acid.

After the fourth liquid is displaced by the fifth liquid, component 100, and in particular layers 130 and 150, are supercritical dried with carbon dioxide. This supercritical drying process includes the use of liquid carbon dioxide. Liquid carbon dioxide is in injected at a high pressure and at a temperature below the supercritical temperature of carbon dioxide into a pressure vessel containing component 100. The liquid carbon dioxide is flowed though the pressure vessel to displace the fifth liquid from between layers 150 and 130. After the fifth liquid is substantially removed, the pressure vessel is heated to above the supercritical temperature. After the pressure vessel and its contents are above the supercritical

10

15

20

temperature, the pressure in the vessel is reduced gradually to atmospheric pressure. Then, the pressure vessel is opened, and the dry component is removed from the pressure vessel.

FIG. 4 illustrates a flow chart 400 of a method of manufacturing a micromachined component such as component 100 of FIGs. 1 through 3. At a step 410 of flow chart 400, a substrate is provided. As an example, the substrate can be similar to substrate 110 of FIGs. 1 through 3.

Next, at a step 420 of flow chart 400 in FIG. 4, a first electrically conductive layer is formed over the substrate. As an example, the first electrically conductive layer can be similar to layer 130 of FIGs. 1 through 3.

Then, at a step 430 in flow chart 400 of FIG. 4, a sacrificial layer is formed over the first electrically conductive layer. As an example, the sacrificial layer can be similar to layer 140 of FIGs. 1 and 2.

Subsequently, at a step 440 of FIG. 4, a second electrically conductive and/or structural layer is formed over the sacrificial layer. As an example, the second electrically conductive and/or structural layer can be similar to layer 150 of FIGs. 1 through 3.

Next, at a step 450 of flow chart 400 in FIG. 4, the second electrically conductive and/or structural layer is patterned. The patterning of the second electrically conductive and/or structural layer exposes portions of the sacrificial layer to permit the subsequent removal of the sacrificial layer.

Then at a step 460 in flow chart 400 of FIG. 4, the second electrically conductive and/or structural layer is removed. The sacrificial layer is etched with a first liquid that is preferably a non-solvent.

10

15

20

Subsequently, at a step 470 of FIG. 4, the first liquid is displaced with a second liquid. As an example, the component can be immersed in the second liquid, or the second liquid can be sprayed onto the component. Step 470 is used to rinse the micromachined component before subsequent processing.

Next, at an optional step 480 of FIG. 4, the second liquid is displaced with a third liquid. As an example, the component can be immersed in the third liquid, or the third liquid can be sprayed onto the component. Step 480 is used to form a stable surface chemistry on the exposed surfaces of the component.

Subsequently, at an optional step 490 of FIG. 4, the third liquid is displaced with a fourth liquid. As an example, the component can be immersed in the fourth liquid, or the fourth liquid can be sprayed onto the component. Step 490 is used to rinse the micromachined component before subsequent processing.

Next, at a step 500 of FIG. 4, the fourth liquid is displaced with a fifth liquid. In an embodiment of flow chart 400 where optional steps 480 and 490 are not performed, step 500 is altered to displace the second liquid with the fifth liquid. The fifth liquid is inorganic and is preferably miscible in carbon dioxide. Step 500 is used to prepare the micromachined component for a subsequent drying process. As an example, the component can be immersed in the fifth liquid, or the fifth liquid can be sprayed onto the component.

In the preferred embodiment, step 500 is performed for approximately five minutes or at least for a sufficiently long enough time to preferably completely remove the fourth liquid. If step 500 is performed by using a static bath of the fifth liquid, the time required for step 500 can increase. If step 500 is performed using a recirculating or agitated bath of the fifth liquid, the time can be decreased.

10

15

Next, at a step 510 of FIG. 4, the micromachined component is supercritical dried, preferably using carbon dioxide. The carbon dioxide displaces the fifth liquid.

Therefore, an improved micromachined component and method of manufacture is provided to overcome the disadvantages of the prior art. The method of manufacturing the micromachined component does significantly increase the manufacturing throughput and also keeps the manufacturing costs low while eliminating or at least reducing release stiction.

Although the invention has been described with reference to specific embodiments, it will be understood by those skilled in the art that various changes may be made without departing from the spirit or scope of the invention. For instance, the numerous details set forth herein such as, for example, the material and liquid compositions are provided to facilitate the understanding of the invention and are not provided to limit the scope of the invention. Accordingly, the disclosure of embodiments of the invention is intended to be illustrative of the scope of the invention and is not intended to be limiting. It is intended that the scope of the invention shall be limited only to the extent required by the appended claims.

CLAIMS

1. A method of manufacturing a micromachined component comprising:
using a first liquid to etch a first layer located underneath a second layer;
exposing the second layer to a second liquid after using the first liquid, the
second liquid being inorganic and miscible in carbon dioxide; and

- supercritical drying the micromachined component with carbon dioxide after exposing the second layer to the second liquid.
 - 2. The method of claim 1 further comprising: forming the first layer comprised of silicon dioxide, and providing the first liquid comprised of hydrofluoric acid.
- 3. The method of claim 1 further comprising:
 forming the first layer comprised of germanium, and
 providing the first liquid comprised of hydrogen peroxide.
- 4. The method of claim 1 further comprising:
 forming the first layer comprised of a polymer, and
 providing the first liquid comprised of an organic solvent.

- 5. The method of claim 1 further comprising: providing the second liquid comprised of carboxylic acid.
- 6. The method of claim 1 further comprising: providing the second liquid comprised of acetic acid.
- 7. The method of claim 1 further comprising:providing the second liquid consisting of glacial acetic acid.
 - 8. The method of claim 1 further comprising:

 exposing the second layer to a third liquid after using the first liquid and before exposing the second layer to the second liquid.
- 9. The method of claim 8 further comprising:providing the first liquid miscible in the third liquid.
 - 10. The method of claim 8 further comprising:

 exposing the second layer to a fourth liquid after exposing the second layer to the third liquid and before exposing the second layer to the second liquid.

- 11. The method of claim 10 further comprising:

 providing the first liquid miscible in the third liquid; and
 providing the third liquid miscible in the fourth liquid.
- 12. The method of claim 10 further comprising:
- 5 exposing the second layer to a fifth liquid after exposing the second layer to the fourth liquid and before exposing the second layer to the second liquid.
- 13. The method of claim 12 further comprising:
 providing the first liquid miscible in the third liquid;
 providing the third liquid miscible in the fourth liquid;
 providing the fourth liquid miscible in the fifth liquid; and
 providing the fifth liquid miscible in the second liquid.
 - 14. The method of claim 12 further comprising: providing a single liquid for the third and fifth liquids.
 - 15. A micromachined component manufactured by the method of claim 1.

16. A method of manufacturing a micromachined component comprising: providing a substrate;

forming a first structural layer over the substrate;

forming a sacrificial layer over the first structural layer;

forming a second structural layer over the sacrificial layer;

patterning the second structural layer;

etching the sacrificial layer with a first liquid;

displacing the first liquid with a second liquid, the first liquid being miscible in the second liquid;

exposing the second structural layer to a third liquid after displacing the first liquid, the third liquid being inorganic and miscible in carbon dioxide; and

supercritical drying the first and second structural layers with carbon dioxide after exposing the second structural layer to the third liquid wherein the carbon dioxide displaces the third liquid.

17. The method of claim 16 further comprising:

providing the first liquid comprised of hydrofluoric acid;

providing the second liquid comprised of deionized water; and

providing the third liquid comprised of carboxylic acid.

18. The method of claim 16 further comprising:

displacing the second liquid with a fourth liquid.

- 19. The method of claim 18 further comprising: providing the second liquid miscible in the fourth liquid.
- 20. The method of claim 18 further comprising: displacing the fourth liquid with a fifth liquid, wherein:

exposing the second structural layer to the third liquid further comprises:

displacing the fifth liquid with the third liquid.

- 21. The method of claim 20 further comprising:
 providing the second liquid miscible in the fourth liquid;
 providing the fourth liquid miscible in the fifth liquid; and
 providing the fifth liquid miscible in the third liquid.
 - 22. The method of claim 21 further comprising: providing a single liquid for the second and fifth liquids.
- 15 23. The method of claim 21 further comprising:
 providing the second liquid comprised of deionized water;
 providing the fourth liquid comprised of hydrogen peroxide;

providing the fifth liquid comprised of deionized water; and providing the third liquid comprised of acetic acid.

- 24. The method of claim 16 further comprising:

 providing the second liquid comprised of deionized water; and
 providing the third liquid comprised of acetic acid,
 wherein:
- 5 exposing the second structural layer to the third liquid further comprises:

displacing the second liquid with the third liquid.

25. A micromachined component manufactured by the method of claim 16.

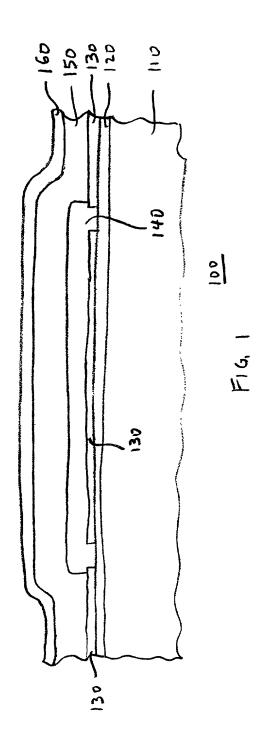
MICROMACHINED COMPONENT AND METHOD OF MANUFACTURE

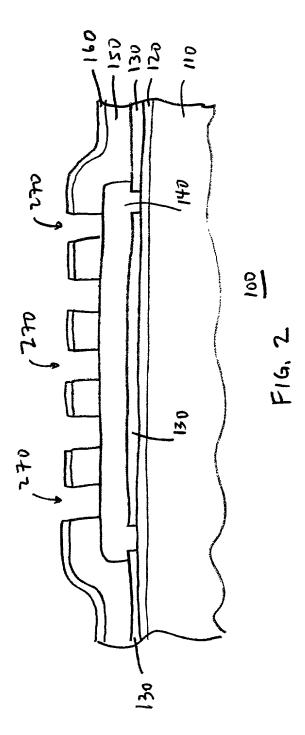
Abstract of the Disclosure

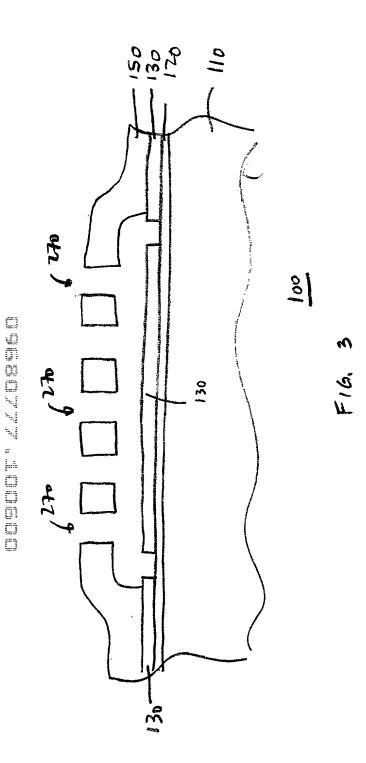
A method of manufacturing a micromachined component includes using a first liquid to etch a first layer (140) located underneath a second layer (150), exposing the second layer to a second liquid that is inorganic and miscible in carbon dioxide, and supercritical drying the micromachined component with carbon dioxide.

10

5







3/3

FIG. 4

<u>400</u>

410	Providing a substrate
	1
420	Forming a first electrically conductive layer over the substrate
	+
430	Forming a sacrificial layer over the first electrically conductive layer
	+
440	Forming a second electrically conductive layer over the sacrificial layer
	<u> </u>
450	Patterning the second electrically conductive layer
	<u> </u>
460	Etching the sacrificial layer with a first liquid
	\
470	Displacing the first liquid with a second liquid
	↓
480	Displacing the second liquid with a third liquid
	↓
490	Displacing the third liquid with a fifth liquid
	↓
500	Displacing the fourth liquid with the fifth liquid, the fifth liquid being inorganic and miscible in carbon dioxide
	↓
510	Supercritical drying the micromachined component with carbon dioxide

COMBINED DECLARATION AND POWER OF ATTORNEY FOR PATENT APPLICATION

Attorney Docket SC11210ZP

As a below named inventor, I hereby declare that:

My residence, post office address and citizenship are as stated below next to my name.

I believe I am the original, first and sole inventor (if only one name is listed below), or an original, first and joint inventor (if plural names are listed below), of the subject matter which is claimed and for which a patent is sought on the invention entitled MICROMACHINED COMPONENT AND METHOD OF MANUFACTURE, the specification of which is attached hereto unless the following box is checked:

11010	to amess the r	Onowing box	is checked.		
	Application vas Application and was ame	on No.			
I he	ereby state the	at I have rev	riewed and under as, as amended by	stand the contents of the	e above-identified above.
I acl	knowledge the ication in acco	e duty to disc rdance with T	lose information vitle 37, Code of Fe	which is material to the parederal Regulations, §1.56.	atentability of this
365(inter Ame inver	b) any foreign national applic rica, listed be	application(station) cation which d low and have te, or of any F	s) for patent or in designated at least also identified be PCT international a	le 35, United States Code eventor's certificate, or 36 one country other than the elow, any foreign applicate application having a filing of	65(a) of any PCT e United States of tion for patent or
Prior	Foreign Appl	ication(s)			Priority Claimed
(Nur	mber)	(Country)		(Day/Month/Year Filed)	Yes No
(Nun	mber)	(Country)		(Day/Month/Year Filed)	Yes No
I her provi	eby claim the isional applicat	benefit under tion(s), listed l	r Title 35, United below:	States Code, § 119 of a	my United States
(App	lication Numb	er)		(Filing Date)	
(Application Number)		(Filing Date)			
r 1	1 1	1 ~ -			

I hereby claim the benefit under Title 35, United States Code, § 120 of any United States application(s), or 365(c) of any PCT international application designating the United States of America, listed below:

(U.S. Parent Application Number or PCT Parent No.)	(Filing Date)	(Country)
(U.S. Parent Application Number or PCT Parent No.)	(Filing Date)	(Country)

I hereby appoint the attorney(s) and/or agent(s) associated with Customer Number 23330 to prosecute this application and to transact all business in the Patent and Trademark Office connected therewith.

Address all telephone calls to Mr. Charles W. Bethards at telephone no. (480) 441-4237.

Address all correspondence to customer number 23330.

I hereby declare that all statements made herein of my own knowledge are true and that all statements made on information and belief are believed to be true; and further that these statements were made with the knowledge that willful false statements and the like so made are punishable by fine or imprisonment, or both, under Section 1001 of Title 18 of the United States Code and that such willful false statements may jeopardize the validity of the application or any patent issued thereon.

FULL NAME OF FIRST INVENTOR: FIRST MIDDLE LAST	INVENTOR'S SIGNATURE:		DATE: (SPELLOUT MONTH)	
Jonathan F. Gorrell				
RESIDENCE:		CITIZENSHIP.		
3241 NE 5th Court, Pompano Beach, FL 33062		United States		
POST OFFICE ADDRESS:				
Same as above				

FULL NAME OF SECOND INVENTOR: FIRST MIDDLE LAST	INVENTOR'S SIGNATURE	INVENTOR'S SIGNATURE		
Gordana S. Nielsen				
RESIDENCE:		CITIZENS	SHIP:	
6602 North 36th Street, Phoenix,	AZ 85018	United	d States	
POST OFFICE ADDRESS:				
Same as above				